# **Power MOSFET**

# 60 V, 4.7 m $\Omega$ , 93 A, Single N-Channel

### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

## **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	60	V
Gate-to-Source Voltage	Э		$V_{GS}$	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	93	Α
Current R <sub>θJC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		65	
Power Dissipation	State	$T_C = 25^{\circ}C$	P <sub>D</sub>	79	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		40	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	20	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		14	
Power Dissipation	State	T <sub>A</sub> = 25°C	P <sub>D</sub>	3.7	W
R <sub>θJA</sub> (Notes 1 & 2)		T <sub>A</sub> = 100°C		1.8	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	750	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	100	Α
Single Pulse Drain–to–Source Avalanche Energy (I <sub>L(pk)</sub> = 5 A)			E <sub>AS</sub>	185	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	1.9	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	41	

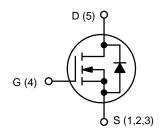
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



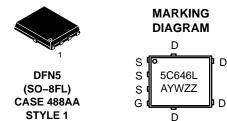
### ON Semiconductor®

### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
60 V	4.7 mΩ @ 10 V	02.4
60 V	6.3 mΩ @ 4.5 V	93 A



**N-CHANNEL MOSFET** 



5C646L = Specific Device Code A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

## ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS							•	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				15.5		mV/°C	
Zero Gate Voltage Drain Current	n Current I <sub>DSS</sub>		$V_{GS} = 0 \text{ V}, \qquad T_{J} = 25 ^{\circ}\text{C}$			10		
		V <sub>DS</sub> = 60 V	T <sub>J</sub> = 125°C			250	μA 50	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	s = 20 V			100	nA	
ON CHARACTERISTICS (Note 4)								
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 80 \mu A$		1.2		2.0	V	
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-4.9		mV/°C	
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		3.8	4.7	0	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 50 A		5.0	6.3	mΩ	
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub>	= 50 A		105		S	
CHARGES, CAPACITANCES & GATE RES	ISTANCE							
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 25 V			2164			
Output Capacitance	C <sub>OSS</sub>				900		pF	
Reverse Transfer Capacitance	C <sub>RSS</sub>				17			
Total Gate Charge	$Q_{G(TOT)}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 30 \text{ V}; I_D = 25 \text{ A}$			15.7			
Total Gate Charge	$Q_{G(TOT)}$	$V_{GS} = 10 \text{ V}, V_{DS} = 30 \text{ V}; I_D = 25 \text{ A}$ $V_{GS} = 4.5 \text{ V}, V_{DS} = 30 \text{ V}; I_D = 25 \text{ A}$			33.7		nC	
Threshold Gate Charge	Q <sub>G(TH)</sub>				1.5			
Gate-to-Source Charge	$Q_{GS}$				5.6			
Gate-to-Drain Charge	$Q_{GD}$				5.1			
Plateau Voltage	V <sub>GP</sub>				2.8		V	
SWITCHING CHARACTERISTICS (Note 5)						•	•	
Turn-On Delay Time	t <sub>d(ON)</sub>				10.4			
Rise Time	t <sub>r</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 30 \text{ V},$ $I_{D} = 25 \text{ A}, R_{G} = 2.5 \Omega$			14.9		1	
Turn-Off Delay Time	t <sub>d(OFF)</sub>				23.6		ns	
Fall Time	t <sub>f</sub>				5.1			
DRAIN-SOURCE DIODE CHARACTERIST	ICS							
Forward Diode Voltage	orward Diode Voltage V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$		0.88	1.2	.,	
		I <sub>S</sub> = 50 A	T <sub>J</sub> = 125°C		0.78		_ V	
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			40.9			
Charge Time	t <sub>a</sub>				20.8		ns	
Discharge Time	t <sub>b</sub>				20.1		1	
Reverse Recovery Charge	Q <sub>RR</sub>				32		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>4.</sup> Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ . 5. Switching characteristics are independent of operating junction temperatures.

### TYPICAL CHARACTERISTICS

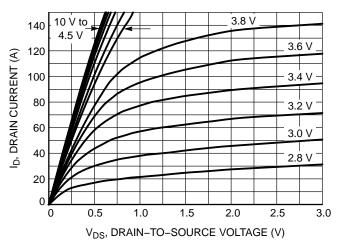


Figure 1. On-Region Characteristics

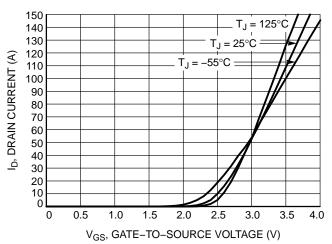


Figure 2. Transfer Characteristics

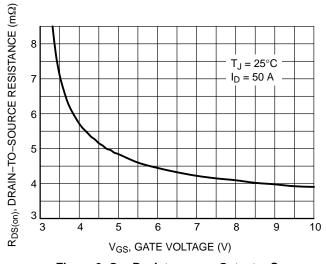


Figure 3. On-Resistance vs. Gate-to-Source Voltage

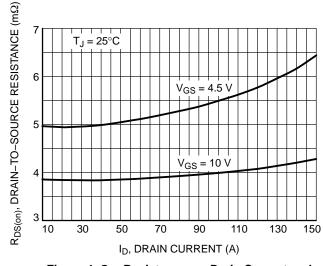


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

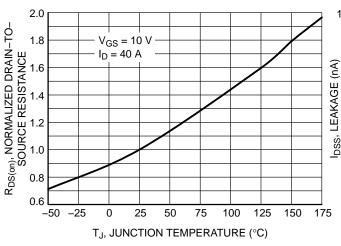


Figure 5. On–Resistance Variation with Temperature

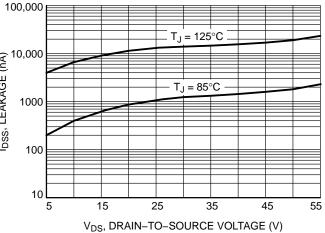


Figure 6. Drain-to-Source Leakage Current vs. Voltage

### TYPICAL CHARACTERISTICS

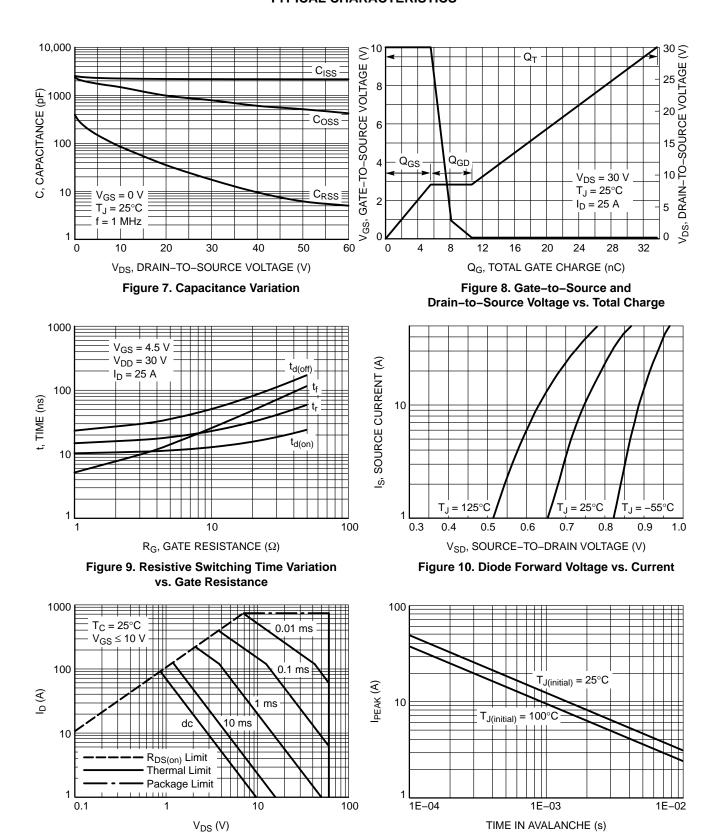


Figure 11. Safe Operating Area

Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

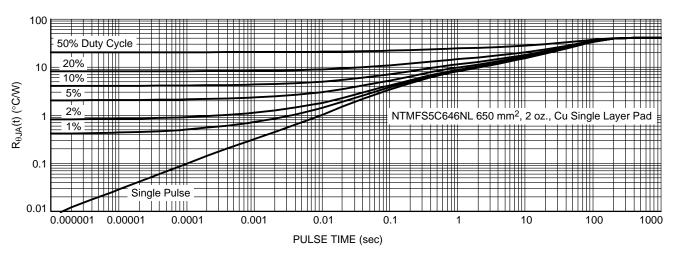


Figure 13. Thermal Characteristics

## **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTMFS5C646NLT1G	5C646L	DFN5 (Pb–Free)	1500 / Tape & Reel
NTMFS5C646NLT3G	5C646L	DFN5 (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



0.10

0.10

SIDE VIEW

DFN5 5x6, 1.27P (SO-8FL) CASE 488AA ISSUE N

**DATE 25 JUN 2018** 

#### NOTES:

BURRS

- DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETER.
  DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	0.90	1.00	1.10	
A1	0.00		0.05	
b	0.33	0.41	0.51	
С	0.23	0.28	0.33	
D	5.00	5.15	5.30	
D1	4.70	4.90	5.10	
D2	3.80	4.00	4.20	
E	6.00	6.15	6.30	
E1	5.70	5.90	6.10	
E2	3.45	3.65	3.85	
е	1.27 BSC			
G	0.51	0.575	0.71	
K	1.20	1.35	1.50	
L	0.51	0.575	0.71	
L1	0.125 REF			
M	3.00	3.40	3.80	
A	0 0		12 °	

### **GENERIC** MARKING DIAGRAM\*

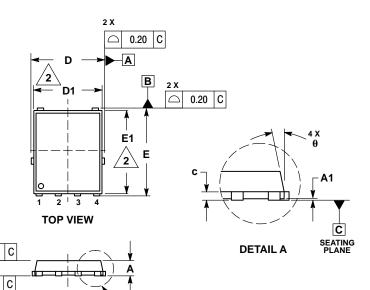


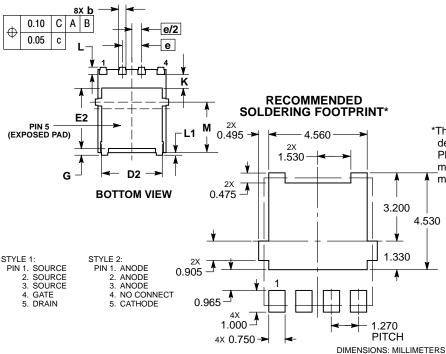
XXXXXX = Specific Device Code

= Assembly Location Α

Υ = Year W = Work Week ZZ = Lot Traceability

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present. Some products may not follow the Generic Marking.





**DETAIL A** 

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	DFN5 5x6, 1.27P (SO-8FL)		PAGE 1 OF 1	

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